

| | | | |
|-----------------------------------|---------------------------------------|---|-------------|
| Notice of References Cited | Application/Control No. 10/005,080 | Applicant(s)/Patent Under Reexamination SMEETS ET AL. | |
| | Examiner Khai M Nguyen | Art Unit 2687 | Page 1 of 1 |

U.S. PATENT DOCUMENTS

| * | | Document Number Country Code-Number-Kind Code | Date MM-YYYY | Name | Classification |
|---|---|--|-----------------|------------------------|----------------|
| | A | US-5,826,186 A | 10-1998 | Mitchell et al. | 455/410 |
| | B | US-6,157,826 A | 12-2000 | Lee, Jae Wook | 455/411 |
| | C | US-6,084,967 A | 07-2000 | Kennedy et al. | 380/247 |
| | D | US-6,128,389 A | 10-2000 | Chan et al. | 380/247 |
| | E | US-5,765,106 A | 06-1998 | Violante et al. | 455/410 |
| | F | US-6,321,094 B1 | 11-2001 | Hayashi et al. | 455/517 |
| | G | US-6,745,326 B1 | 06-2004 | Wary, M. Jean-Philippe | 713/168 |
| | H | US-6,657,538 B1 | 12-2003 | Ritter, Rudolf | 340/5.81 |
| | I | US-5,729,537 | 03-1998 | Billstrom, Lars Axel | 370/329 |
| | J | US-2002/0019223 | 02-2002 | Lee et al. | 455/411 |
| | K | US- | | | |
| | L | US- | | | |
| | M | US- | | | |

FOREIGN PATENT DOCUMENTS

| * | | Document Number Country Code-Number-Kind Code | Date MM-YYYY | Country | Name | Classification |
|---|---|--|-----------------|---------|------|----------------|
| | N | | | | | |
| | O | | | | | |
| | P | | | | | |
| | Q | | | | | |
| | R | | | | | |
| | S | | | | | |
| | T | | | | | |

NON-PATENT DOCUMENTS

| * | | Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages) |
|---|---|---|
| | U | |
| | V | |
| | W | |
| | X | |

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.